

IEEE 1149.4 Mixed-Signal Test Bus Working Group Meeting Minutes

for
September 25th, 2006

8:00AM-10:00AM

Meeting Agenda:

Time	Topic	Responsibility
8:00-10:00 AM	<ol style="list-style-type: none">1. Review the Meeting Minutes on July 19th, 20062. PAR application update3. Update/Review on the following action items:<ol style="list-style-type: none">a. Resolve safe value issueb. Revise Kitchen Sink examplec. Revise Straw Dog exampled. Revise syntax BNFe. Explanation on why disable result for BIDIR shall be Zf. ABSDL for STA400 chip4. Report on 2-day special meeting5. Review comments on the ABSDL draft6. Other issues	All
10:00 AM	Meeting adjourned.	Bambang Suparjo

Meeting Attendees:

Name	Company
Adam Cron	Synopsys
Adam Ley	Asset-Intertech
Ken Parker	Agilent Technologies
Heiko Ehrenberg	Goepel Electronics LLC
Bambang Suparjo	Mentor Graphics

1. Review the Meeting Minutes on July 19th, 2006

The meeting minutes on July 19th, 2006 have been approved, suggested by Ken and seconded by Heiko.

2. PAR Application Update

The PAR application has been approved on September 15, 2006 by the IEEE-SA Standards Board. The project expiration date is December 31, 2010.

3. Update/Review on the following action items:

- a. Resolve safe value issue

The safe value for each cell controlling TBIC and ABM is 0. This is the same value that has been proposed earlier. The explanation will be included in the ABSDL draft.

- b. Revise Kitchen Sink example

This item is still pending.

- c. Revise Straw Dog example

This item is still pending.

- d. Revise syntax BNF

The syntax in BNF has been introduced in the ABSDL draft.

- e. Explanation on why disable result for BIDIR shall be Z

The disable result Z is a good choice for analog pin. However, for digital pin that has dot4 capability, the disable result depends on the existence of pull1, pull0, weak1 and weak0 on that pin.

- f. ABSDL for STA400 chip

Bambang will update the BSDL file using the updated syntax in ABSDL draft.

4. Report on 2-day special meeting

Ken, Adam Cron, Adam Ley, Heiko and Bambang had attended the meeting at Agilent Tech, Loveland, Colorado on August 3-4, 2006. The ABSDL draft has been prepared and distributed to the working group.

5. Review comments on the ABSDL draft

- a. Comment from Philippe Lebourg (ST) regarding a chip has two analog pins AT1 and AT2 and AT2 being reconfigured to AT1N in some cases

As has been informed earlier, this is an ad-hoc usage and it is permitted by the standard as long as it does not interfere with the simple definition of

the standard. However, this case (where AT2 being reconfigured to AT1N) is unable to be described by MST ATAP Identification. The MST ATAP Identification syntax and rules are explained in section 10.4.4.2 in the ABSDL draft.

- b. Request explanation on support for double-bonding-like situation – also from Philippe Lebourg (ST).

The group had a difficulty to understand the issue. Bambang will contact Philippe to get the schematic diagram.

- c. Section 10.4.4.3 – Attribute MST_TestBus_TBIC

For TBIC with partitions, the number of data cells (DATA1s and DATA2s) that can be assigned to capture external digitized values should be only two, one for AT1 and the other for AT2. Hence, there will be only two data cells defined as BIDIR and the other data cells need to be defined as INTERNAL. Additional rules will be included in section 10.4.4.3.2 g and h.

- d. Section 10.4.4.5 – Attribute MST_Diff

Further review is needed on this section.

6. Other Issues

- a. The final presentation slides for the ITC paper have been submitted on September 22, 2006. The presentation rehearsal will be set on October 23, 2006 at 4:00 PM.
- b. The next meeting will be at ITC, on October 26, 2006, 1-3 PM. The meeting will focus on reviewing the ABSDL draft.

- 7. The meeting adjourned at 10:00 AM.